Notification Number:   20161118001   Notification Date:   Dec. 5, 2016		
Customer Contact: PCN Manager Dept: Quality Services  Change Type:  Assembly Site Design Wafer Bump Site Assembly Process Data Sheet Wafer Bump Material Assembly Materials Part number change Wafer Bump Process Mechanical Specification Test Site Wafer Fab Site Packing/Shipping/Labeling Test Process Wafer Fab Materials  Packing/Shipping/Labeling Test Process  Notification Details  Description of Change:  Texas Instruments Incorporated is announcing an information only notification. The product datasheet(s) is updated as seen in the change revision history below:  SN65HVD233-Q1, SN65HVD234-Q1, SN65HVD235-Q1  SLLSES4A - SEPTEMBER 2016 - REVISED NOVEMBER 2016 Changes from Original (September 2016) to Revision A Page  Deleted extra words "all pins except" in the test condition for CANH, CANL pins to GND 5 Added ESD performance information between CANH and CANL pins 5  The datasheet number will be changing.  Device Family Change From: Change To: SN65HVD233-Q1/SN65HVD234-Q1/SN65HVD235-Q1 SLLSES44 SLLSES4A		
Change Type:         □ Assembly Site       □ Design       □ Wafer Bump Site         □ Assembly Process       □ Data Sheet       □ Wafer Bump Material         □ Assembly Materials       □ Part number change       □ Wafer Bump Process         □ Mechanical Specification       □ Test Site       □ Wafer Fab Site         □ Packing/Shipping/Labeling       □ Test Process       □ Wafer Fab Materials         □ Wafer Fab Process         Notification Details         Description of Change:         Texas Instruments Incorporated is announcing an information only notification.         The product datasheet(s) is updated as seen in the change revision history below:         SN65HVD233-Q1, SN65HVD234-Q1, SN65HVD235-Q1         SILISES4A - SEPTEMBER 2016 - REVISED NOVEMBER 2016         Changes from Original (September 2016) to Revision A       Page         • Deleted extra words "all pins except" in the test condition for CANH, CANL pins to GND       5         • Added ESD performance information between CANH and CANL pins       5         The datasheet number will be changing.         Device Family       Change From: Change To: SN65HVD233-Q1/SN65HVD234-Q1/SN65HVD235-Q1       SLLSES4       SLLSES4		
Assembly Site  Design  Data Sheet  Data Sheet  Wafer Bump Material  Assembly Materials  Part number change  Wafer Bump Process  Mechanical Specification  Test Site  Packing/Shipping/Labeling  Test Process  Wafer Fab Materials  Wafer Fab Materials  Wafer Fab Materials  Wafer Fab Process  Notification Details  Description of Change:  Texas Instruments Incorporated is announcing an information only notification.  The product datasheet(s) is updated as seen in the change revision history below:  SN65HVD233-Q1, SN65HVD234-Q1, SN65HVD235-Q1  SLLSES4A - SEPTEMBER 2016 - REVISED NOVEMBER 2016  Changes from Original (September 2016) to Revision A  Page  Deleted extra words "all pins except" in the test condition for CANH, CANL pins to GND  Added ESD performance information between CANH and CANL pins  The datasheet number will be changing.  Device Family  SN65HVD233-Q1/SN65HVD234-Q1/SN65HVD235-Q1  SLLSES4A  SLLSES4A  SLLSES4A		
Assembly Process  Assembly Materials  Part number change  Wafer Bump Material  Wafer Bump Process  Mechanical Specification  Test Site  Packing/Shipping/Labeling  Test Process  Wafer Fab Materials  Wafer Fab Materials  Wafer Fab Process  Notification Details  Description of Change:  Texas Instruments Incorporated is announcing an information only notification. The product datasheet(s) is updated as seen in the change revision history below:  SN65HVD233-Q1, SN65HVD234-Q1, SN65HVD235-Q1  SLLSES4A - SEPTEMBER 2016 - REVISED NOVEMBER 2016  Changes from Original (September 2016) to Revision A  Page  Deleted extra words "all pins except" in the test condition for CANH, CANL pins to GND  Added ESD performance information between CANH and CANL pins  The datasheet number will be changing.  Device Family  SN65HVD233-Q1/SN65HVD234-Q1/SN65HVD235-Q1  SLLSES4  SLLSES4  SLLSES4  SLLSES4  SLLSES4  SLLSES4		
Assembly Materials Part number change Wafer Bump Process Mechanical Specification Test Site Wafer Fab Site Packing/Shipping/Labeling Test Process Wafer Fab Materials Wafer Fab Process Notification Details  Description of Change: Texas Instruments Incorporated is announcing an information only notification. The product datasheet(s) is updated as seen in the change revision history below:  SN65HVD233-Q1, SN65HVD234-Q1, SN65HVD235-Q1 SLLSES4A-SEPTEMBER 2016-REVISED NOVEMBER 2016 Changes from Original (September 2016) to Revision A Page  Deleted extra words "all pins except" in the test condition for CANH, CANL pins to GND 5 Added ESD performance information between CANH and CANL pins to GND 5 The datasheet number will be changing.  Device Family Change From: Change To: SN65HVD233-Q1/SN65HVD234-Q1/SN65HVD235-Q1 SLLSES4 SLLSES4A		
Mechanical Specification  Test Site  Packing/Shipping/Labeling  Test Process  Wafer Fab Materials  Wafer Fab Process  Notification Details  Description of Change:  Texas Instruments Incorporated is announcing an information only notification. The product datasheet(s) is updated as seen in the change revision history below:  SN65HVD233-Q1, SN65HVD234-Q1, SN65HVD235-Q1  SLLSES4A-SEPTEMBER 2016-REVISED NOVEMBER 2016  Changes from Original (September 2016) to Revision A  Page  Deleted extra words "all pins except" in the test condition for CANH, CANL pins to GND  Added ESD performance information between CANH and CANL pins  The datasheet number will be changing.  Device Family  Change From: Change To:  SN65HVD233-Q1/SN65HVD234-Q1/SN65HVD235-Q1  SLLSES4A  SLLSES4A		
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SN65HVD233-Q1/SN65HVD234-Q1/SN65HVD235-Q1 SLLSES4 <b>SLLSES4A</b>		
These changes may be reviewed at the datasheet links provided.		
http://www.ti.com/lit/ds/symlink/sn65hvd234-q1.pdf		
Reason for Change:		
To more accurately reflect device characteristics.		
Anticipated impact on Fit, Form, Function, Quality or Reliability (positive / negative):		
No anticipated impact. This is a specification change announcement only. There are no changes to the actual device		
Changes to product identification resulting from this notification:		
None.		
Product Affected:		
SN65HVD233QDRQ1 SN65HVD234QDRQ1 SN65HVD235QDRQ1		

For questions regarding this notice, e-mails can be sent to the regional contacts shown below or your local Field Sales Representative.

Location	E-Mail
USA	PCNAmericasContact@list.ti.com
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